

(PTO-1449)

APPLN. SERIAL NO.  
09/869,145

**APPLICANT(S)**  
**Hoel Wyul KIM and Sun Kyoo HWANG**

FILING DATE  
**June 26, 2001**

GROUP  
2621

[illegible]

	*PATENT APPLN. PUB. NO.	*PUB. DATE	*APPLICANT	CLASS	SUBCLASS	

	*APPLN. NO.	*FILING DATE	*INVENTOR	CLASS	SUBCLASS	

EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						Yes	No
<i>de</i>	11-256106	09/21/1999	Japan			Abstract	X


EXAMINER

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6.21.04

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ATTY. DOCKET NO.  
**P-224**

APPLN. SERIAL NO.  
**09/869,145**

APPLICANT(S)  
**Hoel Wyul KIM and Sun Kyoo HWANG**

CUSTOMER NO. 34610

FILING DATE  
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**2621**

U.S. PATENT DOCUMENTS

EXAMINER'S INITIALS	*PATENT NO.	*ISSUE DATE	*INVENTOR NAME	CLASS	SUBCLASS	FILING DATE

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U.S. PATENT APPLICATION PUBLICATIONS

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	*APPLN. NO.	*FILING DATE	*INVENTOR	CLASS	SUBCLASS	

FOREIGN PATENT DOCUMENTS

EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						Yes	No
<i>de</i>	JP 09-147109	06/06/1997	Japan (abstract and full text)			X	

OTHER ART (Including Author, Title, Date, Pertinent Pages, Publisher, Place of Publication, Etc.)


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